

Notice of References Cited	Application/Control No. 10/655,900	Applicant(s)/Patent Under Reexamination SHIUE ET AL.	
	Examiner Sayed T. Zewari	Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,934,568	08-2005	Charlier et al.	455/575.3
*	B	US-6,973,186	12-2005	Shin, Ji Seop	379/433.12
*	C	US-6,850,784	02-2005	SanGiovanni, John	455/575.1
*	D	US-6,628,974	09-2003	Lim, Tae Hyeong	455/575.3
*	E	US-6,980,840	12-2005	Kim et al.	455/575.4
*	F	US-2003/0162560	08-2003	Kaneko, Yasuhiro	455/550
*	G	US-6,819,947	11-2004	Okuda et al.	455/575.3
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.